

Search Notes

Application/Control No.

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Examiner

Benjamin E. Lanier

Applicant(s)/Patent under
Reexamination

CHEN, CHIEN-YUAN

Art Unit

2132

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Limited Search of 713/193 726/26-30 See Attachment	4/3/2007	
East Search See Attachment	4/3/2007	
Inventor Name Search Palm	4/4/2007	